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INFORMATEON		Att	Atty. Docket No.: Serial No.:					
DISCLOSURE 56			56331US002 10/027,763					
STATEMENT App			Applicant(s):					
James M. Ne			nes M. Nelson,	lson, Raghunath Padiyath, Robert B. Secor,				
ļ		Ma	rk J. Stevensor	i, Michael J. Tichy	and Robert	A. Yapel		
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OMB No. 0651-0011 Atty. Docket No.: INFORMATION TRADES Serial No.: 56331US002 10/027,763 DISCLOSURE Applicant(s): **STATEMENT** James M. Nelson, Raghunath Padiyath, Robert B. Secor, Mark J. Stevenson, Michael J. Tichy and Robert A. Yapel Filing Date: Group: December 19, 2001 Unknown U.S. PATENT DOCUMENTS Examiner **Document Number** Date Class SubClass Filing Date If Initial Appropriate SS 11/17/1998 5,837,324 Yapel et al. 5,843,530 12/01/1998 Jerry et al. 5,851,137 12/22/1998 Bhave et al. 5,980,992 11/09/1999 Kistner et al. 12/07/1999 5,998,549 Milbourn et al. FOREIGN PATENT DOCUMENTS **Document Number** SubClass Translation Publication Yes No WO 00/06364 / 02/10/2000 PCT WO 95/29763 🖊 11/09/1995 **PCT** WO 95/29764 / 11/09/1995 **PCT** WO 95/29765 / 11/09/1995 **PCT** WO95/29766 ~ 11/09/1995 **PCT** OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.) Catalog, Precision Steel Warehouse, Inc. 1998, Franklin Park, IL (3 pages). Edward Cohen and Edgar Gutoff, "Modern Coating and Drying Technology", VCH Publishers, NY 1992, ISBN 3-527-28246-7 Gutkoff and Cohn, "Coating and Drying Defects: Troubleshooting Operating Problems", Wiley Interscience, NY, ISBN 0-471-59810-0 Bird, Armstrong, and Hassager, Dyamics of Polymeric Liquids, Vol. 1, Wiley & Sons, NY, 1987 ISBN 0-471-80245-S, Chapter 4, pp. 169-175 Robert Secor, "Analysis and Design of Internal Coating Die Cavaties", Stephan Kistler and Peter Schweizer, Liquid Film Coating, Chapman & Hall, UK, 1997, ISBN 0-412-06481-2 22 Research Disclosure, "Die Shims for Modified Film Thickness Profile", May, 1996

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6/25/34

Date Considered

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Filing Date	D cember 19, 2001
First Named Inventor	N Ison, James M.
Art Unit	1722
Examiner Name	

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